

Notice of References Cited		Application/Control No. 10/758,817	Applicant(s)/Patent Under Reexamination MARKS, RICHARD L.	
		Examiner KENT WANG	Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,769,769	08-2004	Podoleanu et al.	351/221
*	B US-6,473,516	10-2002	Kawaguchi et al.	382/100
*	C US-7,061,507	06-2006	Tuomi et al.	345/611
*	D US-2001/0017932	08-2001	Chang, Kenneth H.P.	382/100
*	E US-6,411,392	06-2002	Bender et al.	358/1,14
*	F US-5,870,100	02-1999	DeFreitas, Scott C.	345/441
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Gvili et al. "Depth Keying", SPIE Vol. 5006 (2003), 2003 SPIE-IS&T, pp 564-574
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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